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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

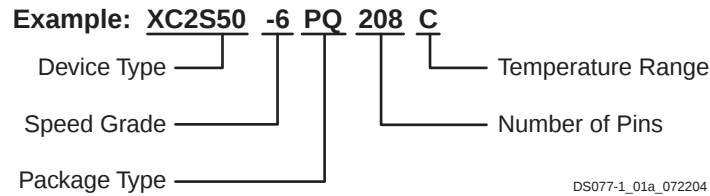
Details

Product Status	Obsolete
Number of LABs/CLBs	216
Number of Logic Elements/Cells	972
Total RAM Bits	24576
Number of I/O	140
Number of Gates	30000
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc2s30-5pq208c

Ordering Information

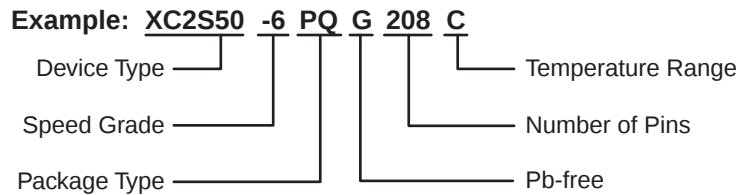
Spartan-II devices are available in both standard and Pb-free packaging options for all device/package combinations. The Pb-free packages include a special "G" character in the ordering code.

Standard Packaging



DS077-1_01a_072204

Pb-Free Packaging



DS077-1_01b_072204

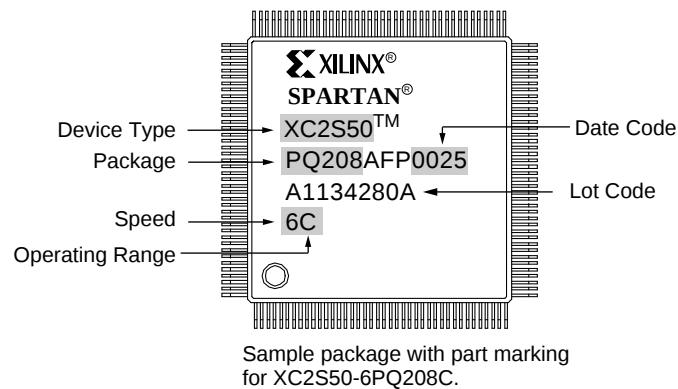
Device Ordering Options

Device	Speed Grade		Number of Pins / Package Type		Temperature Range (T _J)	
XC2S15	-5	Standard Performance	VQ(G)100	100-pin Plastic Very Thin QFP	C = Commercial	0°C to +85°C
XC2S30	-6	Higher Performance ⁽¹⁾	CS(G)144	144-ball Chip-Scale BGA	I = Industrial	-40°C to +100°C
XC2S50			TQ(G)144	144-pin Plastic Thin QFP		
XC2S100			PQ(G)208	208-pin Plastic QFP		
XC2S150			FG(G)256	256-ball Fine Pitch BGA		
XC2S200			FG(G)456	456-ball Fine Pitch BGA		

Notes:

- The -6 speed grade is exclusively available in the Commercial temperature range.

Device Part Marking



ds001-1_02_090303

Architectural Description

Spartan-II FPGA Array

The Spartan®-II field-programmable gate array, shown in [Figure 2](#), is composed of five major configurable elements:

- IOBs provide the interface between the package pins and the internal logic
- CLBs provide the functional elements for constructing most logic
- Dedicated block RAM memories of 4096 bits each
- Clock DLLs for clock-distribution delay compensation and clock domain control
- Versatile multi-level interconnect structure

As can be seen in [Figure 2](#), the CLBs form the central logic structure with easy access to all support and routing structures. The IOBs are located around all the logic and

memory elements for easy and quick routing of signals on and off the chip.

Values stored in static memory cells control all the configurable logic elements and interconnect resources. These values load into the memory cells on power-up, and can reload if necessary to change the function of the device.

Each of these elements will be discussed in detail in the following sections.

Input/Output Block

The Spartan-II FPGA IOB, as seen in [Figure 2](#), features inputs and outputs that support a wide variety of I/O signaling standards. These high-speed inputs and outputs are capable of supporting various state of the art memory and bus interfaces. [Table 3](#) lists several of the standards which are supported along with the required reference, output and termination voltages needed to meet the standard.

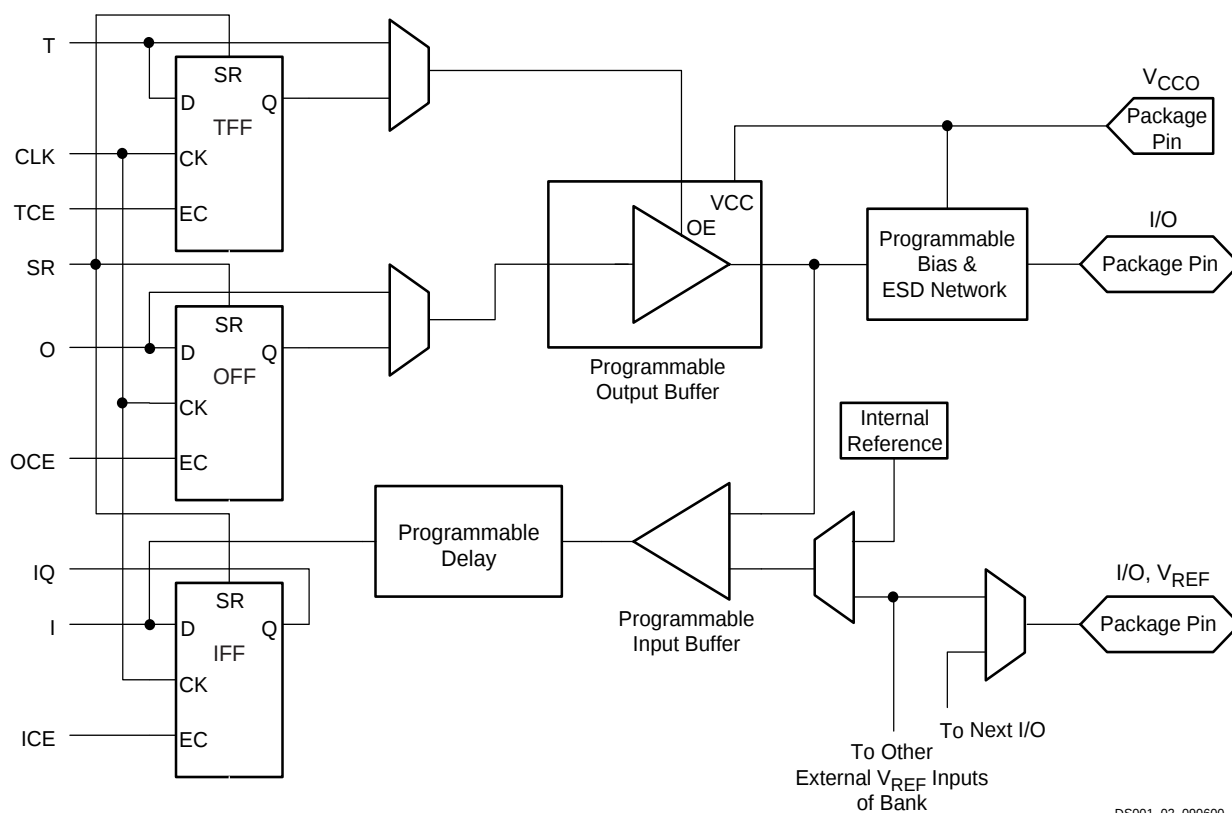


Figure 2: Spartan-II FPGA Input/Output Block (IOB)

Configuration

Configuration is the process by which the bitstream of a design, as generated by the Xilinx software, is loaded into the internal configuration memory of the FPGA. Spartan-II devices support both serial configuration, using the master/slave serial and JTAG modes, as well as byte-wide configuration employing the Slave Parallel mode.

Configuration File

Spartan-II devices are configured by sequentially loading frames of data that have been concatenated into a configuration file. [Table 8](#) shows how much nonvolatile storage space is needed for Spartan-II devices.

It is important to note that, while a PROM is commonly used to store configuration data before loading them into the FPGA, it is by no means required. Any of a number of different kinds of under populated nonvolatile storage already available either on or off the board (i.e., hard drives, FLASH cards, etc.) can be used. For more information on configuration without a PROM, refer to [XAPP098, The Low-Cost, Efficient Serial Configuration of Spartan FPGAs](#).

Table 8: Spartan-II Configuration File Size

Device	Configuration File Size (Bits)
XC2S15	197,696
XC2S30	336,768
XC2S50	559,200
XC2S100	781,216
XC2S150	1,040,096
XC2S200	1,335,840

Modes

Spartan-II devices support the following four configuration modes:

- Slave Serial mode
- Master Serial mode
- Slave Parallel mode
- Boundary-scan mode

The Configuration mode pins (M2, M1, M0) select among these configuration modes with the option in each case of having the IOB pins either pulled up or left floating prior to the end of configuration. The selection codes are listed in [Table 9](#).

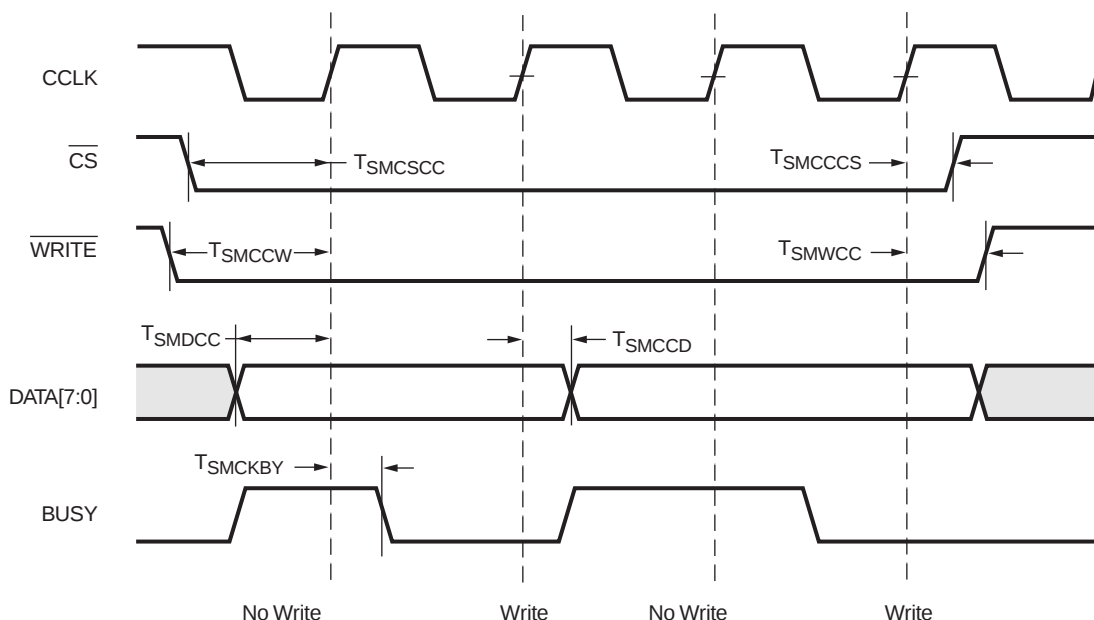
Configuration through the boundary-scan port is always available, independent of the mode selection. Selecting the boundary-scan mode simply turns off the other modes. The three mode pins have internal pull-up resistors, and default to a logic High if left unconnected.

Table 9: Configuration Modes

Configuration Mode	Preconfiguration Pull-ups	M0	M1	M2	CCLK Direction	Data Width	Serial D _{OUT}
Master Serial mode	No	0	0	0	Out	1	Yes
	Yes	0	0	1			
Slave Parallel mode	Yes	0	1	0	In	8	No
	No	0	1	1			
Boundary-Scan mode	Yes	1	0	0	N/A	1	No
	No	1	0	1			
Slave Serial mode	Yes	1	1	0	In	1	Yes
	No	1	1	1			

Notes:

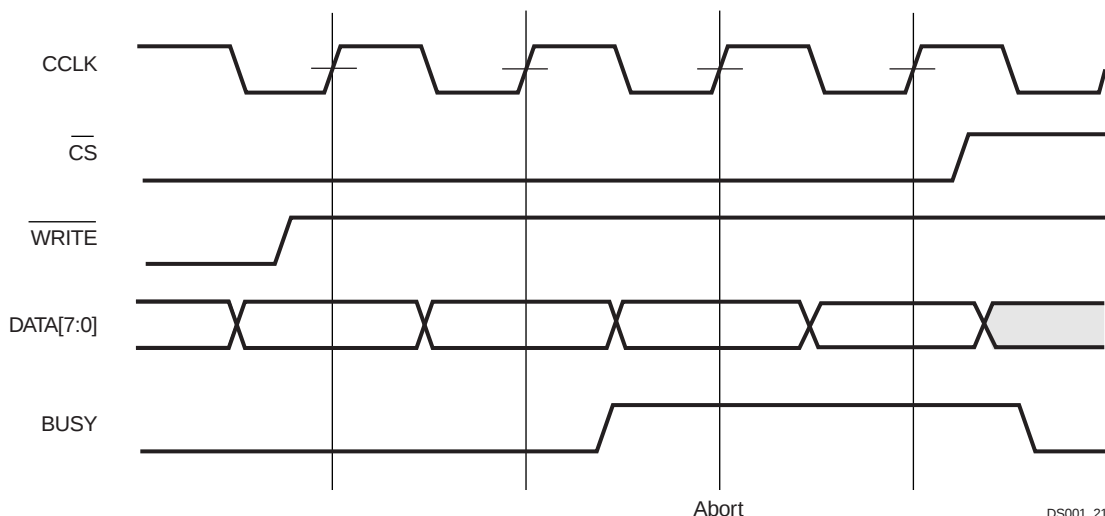
1. During power-on and throughout configuration, the I/O drivers will be in a high-impedance state. After configuration, all unused I/Os (those not assigned signals) will remain in a high-impedance state. Pins used as outputs may pulse High at the end of configuration (see [Answer 10504](#)).
2. If the Mode pins are set for preconfiguration pull-ups, those resistors go into effect once the rising edge of INIT samples the Mode pins. They will stay in effect until GTS is released during startup, after which the UnusedPin bitstream generator option will determine whether the unused I/Os have a pull-up, pull-down, or no resistor.



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Symbol		Description		Units
T_{SMDCC}	CCLK	D0-D7 setup/hold	5	ns, min
T_{SMCCD}		D0-D7 hold	0	ns, min
T_{SMCSCC}		$\overline{CS}$ setup	7	ns, min
T_{SMCCCS}		$\overline{CS}$ hold	0	ns, min
T_{SMCCW}		$\overline{WRITE}$ setup	7	ns, min
T_{SMWCC}		$\overline{WRITE}$ hold	0	ns, min
T_{SMCKBY}		BUSY propagation delay	12	ns, max
F_{CC}		Maximum frequency	66	MHz, max
F_{CCNH}		Maximum frequency with no handshake	50	MHz, max

Figure 20: Slave Parallel Write Timing



Abort

DS001_21_032300

Figure 21: Slave Parallel Write Abort Waveforms

Design Considerations

This section contains more detailed design information on the following features:

- Delay-Locked Loop . . . see [page 27](#)
- Block RAM . . . see [page 32](#)
- Versatile I/O . . . see [page 36](#)

Using Delay-Locked Loops

The Spartan-II FPGA family provides up to four fully digital dedicated on-chip Delay-Locked Loop (DLL) circuits which provide zero propagation delay, low clock skew between output clock signals distributed throughout the device, and advanced clock domain control. These dedicated DLLs can be used to implement several circuits that improve and simplify system level design.

Introduction

Quality on-chip clock distribution is important. Clock skew and clock delay impact device performance and the task of managing clock skew and clock delay with conventional clock trees becomes more difficult in large devices. The Spartan-II family of devices resolve this potential problem by providing up to four fully digital dedicated on-chip Delay-Locked Loop (DLL) circuits which provide zero propagation delay and low clock skew between output clock signals distributed throughout the device.

Each DLL can drive up to two global clock routing networks within the device. The global clock distribution network minimizes clock skews due to loading differences. By monitoring a sample of the DLL output clock, the DLL can compensate for the delay on the routing network, effectively eliminating the delay from the external input port to the individual clock loads within the device.

In addition to providing zero delay with respect to a user source clock, the DLL can provide multiple phases of the source clock. The DLL can also act as a clock doubler or it can divide the user source clock by up to 16.

Clock multiplication gives the designer a number of design alternatives. For instance, a 50 MHz source clock doubled by the DLL can drive an FPGA design operating at 100 MHz. This technique can simplify board design because the clock path on the board no longer distributes such a high-speed signal. A multiplied clock also provides designers the option of time-domain-multiplexing, using one circuit twice per clock cycle, consuming less area than two copies of the same circuit.

The DLL can also act as a clock mirror. By driving the DLL output off-chip and then back in again, the DLL can be used to de-skew a board level clock between multiple devices.

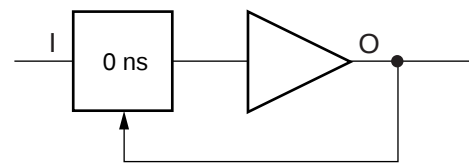
In order to guarantee the system clock establishes prior to the device "waking up," the DLL can delay the completion of

the device configuration process until after the DLL achieves lock.

By taking advantage of the DLL to remove on-chip clock delay, the designer can greatly simplify and improve system level design involving high-fanout, high-performance clocks.

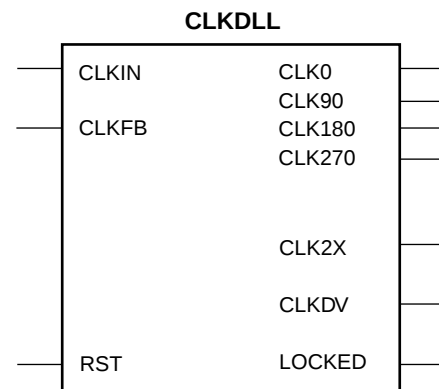
Library DLL Primitives

Figure 22 shows the simplified Xilinx library DLL macro, BUFGDLL. This macro delivers a quick and efficient way to provide a system clock with zero propagation delay throughout the device. Figure 23 and Figure 24 show the two library DLL primitives. These primitives provide access to the complete set of DLL features when implementing more complex applications.



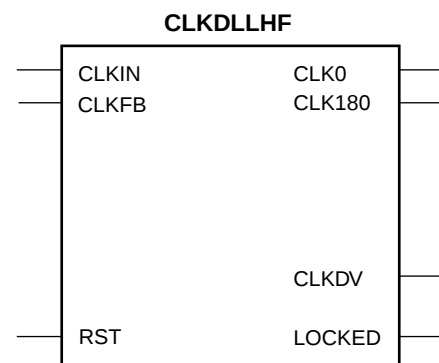
DS001_22_032300

Figure 22: Simplified DLL Macro BUFGDLL



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Figure 23: Standard DLL Primitive CLKDLL



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Figure 24: High-Frequency DLL Primitive CLKDLLHF

LVTTL output buffers have selectable drive strengths.

The format for LVTTL OBUF primitive names is as follows.

OBUF_<slew_rate>_<drive_strength>

<slew_rate> is either F (Fast), or S (Slow) and <drive_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24). The default is slew rate limited with 12 mA drive.

OBUF placement restrictions require that within a given V_{CCO} bank each OBUF share the same output source drive voltage. Input buffers of any type and output buffers that do not require V_{CCO} can be placed within any V_{CCO} bank.

Table 17 summarizes the output compatibility requirements. The LOC property can specify a location for the OBUF.

Table 17: Output Standards Compatibility Requirements

Rule 1	Only outputs with standards which share compatible V_{CCO} may be used within the same bank.
Rule 2	There are no placement restrictions for outputs with standards that do not require a V_{CCO} .
V_{CCO}	Compatible Standards
3.3	LVTTL, SSTL3_I, SSTL3_II, CTT, AGP, GTL, GTL+, PCI33_3, PCI66_3
2.5	SSTL2_I, SSTL2_II, LVCMOS2, GTL, GTL+
1.5	HSTL_I, HSTL_III, HSTL_IV, GTL, GTL+

OBUFT

The generic 3-state output buffer OBUFT, shown in Figure 39, typically implements 3-state outputs or bidirectional I/O.

With no extension or property specified for the generic OBUFT primitive, the assumed standard is slew rate limited LVTTL with 12 mA drive strength.

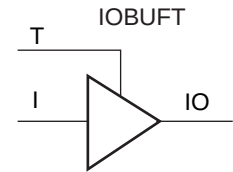
The LVTTL OBUFT can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL 3-state output buffers have selectable drive strengths.

The format for LVTTL OBUFT primitive names is as follows.

OBUFT_<slew_rate>_<drive_strength>

<slew_rate> can be either F (Fast), or S (Slow) and <drive_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24).



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Figure 39: 3-State Output Buffer Primitive (OBUFT)

The Versatile I/O OBUFT placement restrictions require that within a given V_{CCO} bank each OBUFT share the same output source drive voltage. Input buffers of any type and output buffers that do not require V_{CCO} can be placed within the same V_{CCO} bank.

The LOC property can specify a location for the OBUFT.

3-state output buffers and bidirectional buffers can have either a weak pull-up resistor, a weak pull-down resistor, or a weak "keeper" circuit. Control this feature by adding the appropriate primitive to the output net of the OBUFT (PULLUP, PULLDOWN, or KEEPER).

The weak "keeper" circuit requires the input buffer within the IOB to sample the I/O signal. So, OBUFTs programmed for an I/O standard that requires a V_{REF} have automatic placement of a V_{REF} in the bank with an OBUFT configured with a weak "keeper" circuit. This restriction does not affect most circuit design as applications using an OBUFT configured with a weak "keeper" typically implement a bidirectional I/O. In this case the IBUF (and the corresponding V_{REF}) are explicitly placed.

The LOC property can specify a location for the OBUFT.

IOBUF

Use the IOBUF primitive for bidirectional signals that require both an input buffer and a 3-state output buffer with an active high 3-state pin. The generic input/output buffer IOBUF appears in Figure 40.

With no extension or property specified for the generic IOBUF primitive, the assumed standard is LVTTL input buffer and slew rate limited LVTTL with 12 mA drive strength for the output buffer.

The LVTTL IOBUF can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL bidirectional buffers have selectable output drive strengths.

The format for LVTTL IOBUF primitive names is as follows:

property. This property could have one of the following seven values.

DRIVE=2
 DRIVE=4
 DRIVE=6
 DRIVE=8
 DRIVE=12 (Default)
 DRIVE=16
 DRIVE=24

Design Considerations

Reference Voltage (V_{REF}) Pins

Low-voltage I/O standards with a differential amplifier input buffer require an input reference voltage (V_{REF}). Provide the V_{REF} as an external signal to the device.

The voltage reference signal is "banked" within the device on a half-edge basis such that for all packages there are eight independent V_{REF} banks internally. See [Figure 36, page 39](#) for a representation of the I/O banks. Within each bank approximately one of every six I/O pins is automatically configured as a V_{REF} input.

Within each V_{REF} bank, any input buffers that require a V_{REF} signal must be of the same type. Output buffers of any type and input buffers can be placed without requiring a reference voltage within the same V_{REF} bank.

Output Drive Source Voltage (V_{CCO}) Pins

Many of the low voltage I/O standards supported by Versatile I/Os require a different output drive source voltage (V_{CCO}). As a result each device can often have to support multiple output drive source voltages.

The V_{CCO} supplies are internally tied together for some packages. The VQ100 and the PQ208 provide one combined V_{CCO} supply. The TQ144 and the CS144 packages provide four independent V_{CCO} supplies. The FG256 and the FG456 provide eight independent V_{CCO} supplies.

Output buffers within a given V_{CCO} bank must share the same output drive source voltage. Input buffers for LVTTTL, LVCMOS2, PCI33_3, and PCI 66_3 use the V_{CCO} voltage for Input V_{CCO} voltage.

Transmission Line Effects

The delay of an electrical signal along a wire is dominated by the rise and fall times when the signal travels a short distance. Transmission line delays vary with inductance and capacitance, but a well-designed board can experience delays of approximately 180 ps per inch.

Transmission line effects, or reflections, typically start at 1.5" for fast (1.5 ns) rise and fall times. Poor (or non-existent) termination or changes in the transmission line impedance cause these reflections and can cause additional delay in longer traces. As system speeds continue to increase, the effect of I/O delays can become a limiting factor and therefore transmission line termination becomes increasingly more important.

Termination Techniques

A variety of termination techniques reduce the impact of transmission line effects.

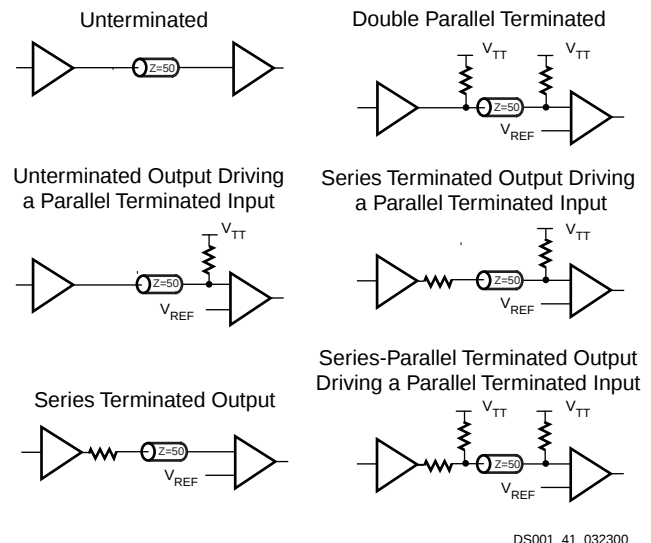
The following lists output termination techniques:

None
 Series
 Parallel (Shunt)
 Series and Parallel (Series-Shunt)

Input termination techniques include the following:

None
 Parallel (Shunt)

These termination techniques can be applied in any combination. A generic example of each combination of termination methods appears in [Figure 41](#).



DS001_41_032300

Figure 41: Overview of Standard Input and Output Termination Methods

Simultaneous Switching Guidelines

Ground bounce can occur with high-speed digital ICs when multiple outputs change states simultaneously, causing undesired transient behavior on an output, or in the internal logic. This problem is also referred to as the Simultaneous Switching Output (SSO) problem.

Ground bounce is primarily due to current changes in the combined inductance of ground pins, bond wires, and

SSTL3 Class I

A sample circuit illustrating a valid termination technique for SSTL3_I appears in Figure 47. DC voltage specifications appear in Table 25 for the SSTL3_I standard. See "DC Specifications" in Module 3 for the actual FPGA characteristics.

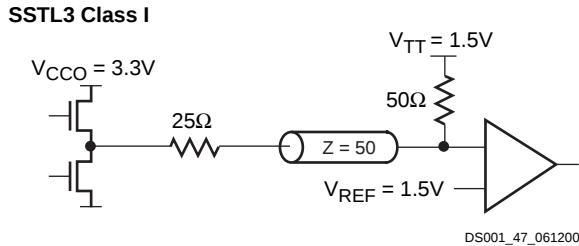


Figure 47: Terminated SSTL3 Class I

Table 25: SSTL3_I Voltage Specifications

Parameter	Min	Typ	Max
V_{CCO}	3.0	3.3	3.6
$V_{REF} = 0.45 \times V_{CCO}$	1.3	1.5	1.7
$V_{TT} = V_{REF}$	1.3	1.5	1.7
$V_{IH} \geq V_{REF} + 0.2$	1.5	1.7	3.9 ⁽¹⁾
$V_{IL} \leq V_{REF} - 0.2$	-0.3 ⁽²⁾	1.3	1.5
$V_{OH} \geq V_{REF} + 0.6$	1.9	-	-
$V_{OL} \leq V_{REF} - 0.6$	-	-	1.1
I_{OH} at V_{OH} (mA)	-8	-	-
I_{OL} at V_{OL} (mA)	8	-	-

Notes:

- V_{IH} maximum is $V_{CCO} + 0.3$.
- V_{IL} minimum does not conform to the formula.

SSTL3 Class II

A sample circuit illustrating a valid termination technique for SSTL3_II appears in Figure 48. DC voltage specifications appear in Table 26 for the SSTL3_II standard. See "DC Specifications" in Module 3 for the actual FPGA characteristics.

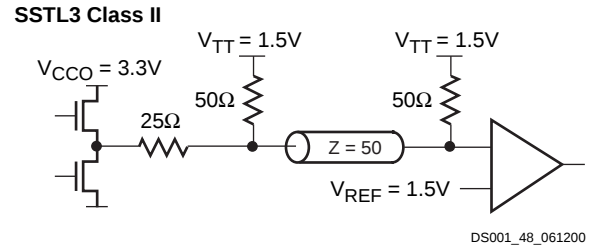


Figure 48: Terminated SSTL3 Class II

Table 26: SSTL3_II Voltage Specifications

Parameter	Min	Typ	Max
V_{CCO}	3.0	3.3	3.6
$V_{REF} = 0.45 \times V_{CCO}$	1.3	1.5	1.7
$V_{TT} = V_{REF}$	1.3	1.5	1.7
$V_{IH} \geq V_{REF} + 0.2$	1.5	1.7	3.9 ⁽¹⁾
$V_{IL} \leq V_{REF} - 0.2$	-0.3 ⁽²⁾	1.3	1.5
$V_{OH} \geq V_{REF} + 0.8$	2.1	-	-
$V_{OL} \leq V_{REF} - 0.8$	-	-	0.9
I_{OH} at V_{OH} (mA)	-16	-	-
I_{OL} at V_{OL} (mA)	16	-	-

Notes:

- V_{IH} maximum is $V_{CCO} + 0.3$.
- V_{IL} minimum does not conform to the formula.

LVTTTL

LVTTTL requires no termination. DC voltage specifications appears in [Table 32](#) for the LVTTTL standard. See "[DC Specifications](#)" in Module 3 for the actual FPGA characteristics.

Table 32: LVTTTL Voltage Specifications

Parameter	Min	Typ	Max
V_{CCO}	3.0	3.3	3.6
V_{REF}	-	-	-
V_{TT}	-	-	-
V_{IH}	2.0	-	5.5
V_{IL}	-0.5	-	0.8
V_{OH}	2.4	-	-
V_{OL}	-	-	0.4
I_{OH} at V_{OH} (mA)	-24	-	-
I_{OL} at V_{OL} (mA)	24	-	-

Notes:

1. V_{OL} and V_{OH} for lower drive currents sample tested.

LVC MOS2

LVC MOS2 requires no termination. DC voltage specifications appear in [Table 33](#) for the LVC MOS2 standard. See "[DC Specifications](#)" in Module 3 for the actual FPGA characteristics.

Table 33: LVC MOS2 Voltage Specifications

Parameter	Min	Typ	Max
V_{CCO}	2.3	2.5	2.7
V_{REF}	-	-	-
V_{TT}	-	-	-
V_{IH}	1.7	-	5.5
V_{IL}	-0.5	-	0.7
V_{OH}	1.9	-	-
V_{OL}	-	-	0.4
I_{OH} at V_{OH} (mA)	-12	-	-
I_{OL} at V_{OL} (mA)	12	-	-

AGP-2X

The specification for the AGP-2X standard does not document a recommended termination technique. DC voltage specifications appear in [Table 34](#) for the AGP-2X standard. See "[DC Specifications](#)" in Module 3 for the actual FPGA characteristics.

Table 34: AGP-2X Voltage Specifications

Parameter	Min	Typ	Max
V_{CCO}	3.0	3.3	3.6
$V_{REF} = N \times V_{CCO}^{(1)}$	1.17	1.32	1.48
V_{TT}	-	-	-
$V_{IH} \geq V_{REF} + 0.2$	1.37	1.52	-
$V_{IL} \leq V_{REF} - 0.2$	-	1.12	1.28
$V_{OH} \geq 0.9 \times V_{CCO}$	2.7	3.0	-
$V_{OL} \leq 0.1 \times V_{CCO}$	-	0.33	0.36
I_{OH} at V_{OH} (mA)	Note 2	-	-
I_{OL} at V_{OL} (mA)	Note 2	-	-

Notes:

1. N must be greater than or equal to 0.39 and less than or equal to 0.41.
2. Tested according to the relevant specification.

For design examples and more information on using the I/O, see [XAPP179](#), *Using SelectIO Interfaces in Spartan-II and Spartan-IIe FPGAs*.

Input/Output Standard	V_{IL}		V_{IH}		V_{OL}	V_{OH}	I_{OL}	I_{OH}
	V, Min	V, Max	V, Min	V, Max	V, Max	V, Min	mA	mA
CTT	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	$V_{REF} - 0.4$	$V_{REF} + 0.4$	8	-8
AGP	-0.5	$V_{REF} - 0.2$	$V_{REF} + 0.2$	3.6	10% V_{CCO}	90% V_{CCO}	Note (2)	Note (2)

Notes:

1. V_{OL} and V_{OH} for lower drive currents are sample tested.
2. Tested according to the relevant specifications.

Switching Characteristics

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE

in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-II devices unless otherwise noted.

Global Clock Input to Output Delay for LVTTL, with DLL (Pin-to-Pin)⁽¹⁾

Symbol	Description	Device	Speed Grade			Units
			All	-6	-5	
			Min	Max	Max	
$T_{ICKOFDLL}$	Global clock input to output delay using output flip-flop for LVTTL, 12 mA, fast slew rate, <i>with</i> DLL.	All		2.9	3.3	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see the tables ["Constants for Calculating TIOOP"](#) and ["Delay Measurement Methodology," page 60](#).
3. DLL output jitter is already included in the timing calculation.
4. For data *output* with different standards, adjust delays with the values shown in ["IOB Output Delay Adjustments for Different Standards," page 59](#). For a global clock input with standards other than LVTTL, adjust delays with values from the ["I/O Standard Global Clock Input Adjustments," page 61](#).

Global Clock Input to Output Delay for LVTTL, without DLL (Pin-to-Pin)⁽¹⁾

Symbol	Description	Device	Speed Grade			Units
			All	-6	-5	
			Min	Max	Max	
T_{ICKOF}	Global clock input to output delay using output flip-flop for LVTTL, 12 mA, fast slew rate, <i>without</i> DLL.	XC2S15		4.5	5.4	ns
		XC2S30		4.5	5.4	ns
		XC2S50		4.5	5.4	ns
		XC2S100		4.6	5.5	ns
		XC2S150		4.6	5.5	ns
		XC2S200		4.7	5.6	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at 1.4V with 35 pF external capacitive load for LVTTL. The 35 pF load does not apply to the Min values. For other I/O standards and different loads, see the tables ["Constants for Calculating TIOOP"](#) and ["Delay Measurement Methodology," page 60](#).
3. For data *output* with different standards, adjust delays with the values shown in ["IOB Output Delay Adjustments for Different Standards," page 59](#). For a global clock input with standards other than LVTTL, adjust delays with values from the ["I/O Standard Global Clock Input Adjustments," page 61](#).

Calculation of T_{IOOP} as a Function of Capacitance

T_{IOOP} is the propagation delay from the O Input of the IOB to the pad. The values for T_{IOOP} are based on the standard capacitive load (C_{SL}) for each I/O standard as listed in the table "Constants for Calculating T_{IOOP} ", below.

For other capacitive loads, use the formulas below to calculate an adjusted propagation delay, T_{IOOP1} .

$$T_{IOOP1} = T_{IOOP} + Adj + (C_{LOAD} - C_{SL}) * F_L$$

Where:

Adj is selected from "IOB Output Delay Adjustments for Different Standards", page 59, according to the I/O standard used

C_{LOAD} is the capacitive load for the design

F_L is the capacitance scaling factor

Delay Measurement Methodology

Standard	$V_L^{(1)}$	$V_H^{(1)}$	Meas. Point	V_{REF} Typ ⁽²⁾
LVTTL	0	3	1.4	-
LVC MOS2	0	2.5	1.125	-
PCI33_5	Per PCI Spec			-
PCI33_3	Per PCI Spec			-
PCI66_3	Per PCI Spec			-
GTL	$V_{REF} - 0.2$	$V_{REF} + 0.2$	V_{REF}	0.80
GTL+	$V_{REF} - 0.2$	$V_{REF} + 0.2$	V_{REF}	1.0
HSTL Class I	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.75
HSTL Class III	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
HSTL Class IV	$V_{REF} - 0.5$	$V_{REF} + 0.5$	V_{REF}	0.90
SSTL3 I and II	$V_{REF} - 1.0$	$V_{REF} + 1.0$	V_{REF}	1.5
SSTL2 I and II	$V_{REF} - 0.75$	$V_{REF} + 0.75$	V_{REF}	1.25
CTT	$V_{REF} - 0.2$	$V_{REF} + 0.2$	V_{REF}	1.5
AGP	$V_{REF} - (0.2 \times V_{CCO})$	$V_{REF} + (0.2 \times V_{CCO})$	V_{REF}	Per AGP Spec

Notes:

- Input waveform switches between V_L and V_H .
- Measurements are made at V_{REF} Typ, Maximum, and Minimum. Worst-case values are reported.
- I/O parameter measurements are made with the capacitance values shown in the table, "Constants for Calculating T_{IOOP} ". See Xilinx application note [XAPP179](#) for the appropriate terminations.
- I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.

Constants for Calculating T_{IOOP}

Standard	$C_{SL}^{(1)}$ (pF)	F_L (ns/pF)
LVTTL Fast Slew Rate, 2 mA drive	35	0.41
LVTTL Fast Slew Rate, 4 mA drive	35	0.20
LVTTL Fast Slew Rate, 6 mA drive	35	0.13
LVTTL Fast Slew Rate, 8 mA drive	35	0.079
LVTTL Fast Slew Rate, 12 mA drive	35	0.044
LVTTL Fast Slew Rate, 16 mA drive	35	0.043
LVTTL Fast Slew Rate, 24 mA drive	35	0.033
LVTTL Slow Slew Rate, 2 mA drive	35	0.41
LVTTL Slow Slew Rate, 4 mA drive	35	0.20
LVTTL Slow Slew Rate, 6 mA drive	35	0.100
LVTTL Slow Slew Rate, 8 mA drive	35	0.086
LVTTL Slow Slew Rate, 12 mA drive	35	0.058
LVTTL Slow Slew Rate, 16 mA drive	35	0.050
LVTTL Slow Slew Rate, 24 mA drive	35	0.048
LVC MOS2	35	0.041
PCI 33 MHz 5V	50	0.050
PCI 33 MHz 3.3V	10	0.050
PCI 66 MHz 3.3V	10	0.033
GTL	0	0.014
GTL+	0	0.017
HSTL Class I	20	0.022
HSTL Class III	20	0.016
HSTL Class IV	20	0.014
SSTL2 Class I	30	0.028
SSTL2 Class II	30	0.016
SSTL3 Class I	30	0.029
SSTL3 Class II	30	0.016
CTT	20	0.035
AGP	10	0.037

Notes:

- I/O parameter measurements are made with the capacitance values shown above. See Xilinx application note [XAPP179](#) for the appropriate terminations.
- I/O standard measurements are reflected in the IBIS model information except where the IBIS format precludes it.

CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-6		-5		
		Min	Max	Min	Max	
Sequential Delays						
T _{SHCKO16}	Clock CLK to X/Y outputs (WE active, 16 x 1 mode)	-	2.2	-	2.6	ns
T _{SHCKO32}	Clock CLK to X/Y outputs (WE active, 32 x 1 mode)	-	2.5	-	3.0	ns
Setup/Hold Times with Respect to Clock CLK ⁽¹⁾						
T _{AS} / T _{AH}	F/G address inputs	0.7 / 0	-	0.7 / 0	-	ns
T _{DS} / T _{DH}	BX/BY data inputs (DIN)	0.8 / 0	-	0.9 / 0	-	ns
T _{WS} / T _{WH}	CE input (WS)	0.9 / 0	-	1.0 / 0	-	ns
Clock CLK						
T _{WPH}	Minimum pulse width, High	-	2.9	-	2.9	ns
T _{WPL}	Minimum pulse width, Low	-	2.9	-	2.9	ns
T _{WC}	Minimum clock period to meet address write cycle time	-	5.8	-	5.8	ns

Notes:

1. A zero hold time listing indicates no hold time or a negative hold time.

CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		-6		-5		
		Min	Max	Min	Max	
Sequential Delays						
T _{REG}	Clock CLK to X/Y outputs	-	3.47	-	3.88	ns
Setup Times with Respect to Clock CLK						
T _{SHDICK}	BX/BY data inputs (DIN)	0.8	-	0.9	-	ns
T _{SHCECK}	CE input (WS)	0.9	-	1.0	-	ns
Clock CLK						
T _{SRPH}	Minimum pulse width, High	-	2.9	-	2.9	ns
T _{SRPL}	Minimum pulse width, Low	-	2.9	-	2.9	ns

Block RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-6		-5		
		Min	Max	Min	Max	
Sequential Delays						
T _{BCKO}	Clock CLK to DOUT output	-	3.4	-	4.0	ns
Setup/Hold Times with Respect to Clock CLK ⁽¹⁾						
T _{BACK} / T _{BCKA}	ADDR inputs	1.4 / 0	-	1.4 / 0	-	ns
T _{BDCK} / T _{BCKD}	DIN inputs	1.4 / 0	-	1.4 / 0	-	ns
T _{BECK} / T _{BCKE}	EN inputs	2.9 / 0	-	3.2 / 0	-	ns
T _{BRCK} / T _{BCKR}	RST input	2.7 / 0	-	2.9 / 0	-	ns
T _{BWCK} / T _{BCKW}	WEN input	2.6 / 0	-	2.8 / 0	-	ns
Clock CLK						
T _{BPWH}	Minimum pulse width, High	-	1.9	-	1.9	ns
T _{BPWL}	Minimum pulse width, Low	-	1.9	-	1.9	ns
T _{BCCS}	CLKA -> CLKB setup time for different ports	-	3.0	-	4.0	ns

Notes:

1. A zero hold time listing indicates no hold time or a negative hold time.

TBUF Switching Characteristics

Symbol	Description	Speed Grade		Units
		-6	-5	
		Max	Max	
Combinatorial Delays				
T _{IO}	IN input to OUT output	0	0	ns
T _{OFF}	TRI input to OUT output high impedance	0.1	0.2	ns
T _{ON}	TRI input to valid data on OUT output	0.1	0.2	ns

JTAG Test Access Port Switching Characteristics

Symbol	Description	Speed Grade				Units
		-6		-5		
		Min	Max	Min	Max	
Setup and Hold Times with Respect to TCK						
T _{TAPTCK} / T _{TCKTAP}	TMS and TDI setup and hold times	4.0 / 2.0	-	4.0 / 2.0	-	ns
Sequential Delays						
T _{TCKTDO}	Output delay from clock TCK to output TDO	-	11.0	-	11.0	ns
f _{TCK}	Maximum TCK clock frequency	-	33	-	33	MHz

XC2S15 Device Pinouts (Continued)

XC2S15 Pad Name		VQ100	TQ144	CS144	Bndry Scan
Function	Bank				
GND	-	-	P61	J12	-
I/O (D5)	3	P57	P60	J13	245
I/O	3	P58	P59	H10	248
I/O, V _{REF}	3	P59	P58	H11	251
I/O (D4)	3	P60	P57	H12	254
I/O	3	-	P56	H13	257
V _{CCINT}	-	P61	P55	G12	-
I/O, TRDY ⁽¹⁾	3	P62	P54	G13	260
V _{CCO}	3	P63	P53	G11	-
V _{CCO}	2	P63	P53	G11	-
GND	-	P64	P52	G10	-
I/O, IRDY ⁽¹⁾	2	P65	P51	F13	263
I/O	2	-	P50	F12	266
I/O (D3)	2	P66	P49	F11	269
I/O, V _{REF}	2	P67	P48	F10	272
I/O	2	P68	P47	E13	275
I/O (D2)	2	P69	P46	E12	278
GND	-	-	P45	E11	-
I/O (D1)	2	P70	P44	E10	281
I/O	2	P71	P43	D13	284
I/O, V _{REF}	2	P72	P41	D11	287
I/O	2	-	P40	C13	290
I/O (DIN, D0)	2	P73	P39	C12	293
I/O (DOUT, BUSY)	2	P74	P38	C11	296
CCLK	2	P75	P37	B13	299
V _{CCO}	2	P76	P36	B12	-
V _{CCO}	1	P76	P35	A13	-
TDO	2	P77	P34	A12	-
GND	-	P78	P33	B11	-
TDI	-	P79	P32	A11	-
I/O ($\overline{\text{CS}}$)	1	P80	P31	D10	0
I/O ($\overline{\text{WRITE}}$)	1	P81	P30	C10	3
I/O	1	-	P29	B10	6
I/O, V _{REF}	1	P82	P28	A10	9
I/O	1	P83	P27	D9	12
I/O	1	P84	P26	C9	15
GND	-	-	P25	B9	-
V _{CCINT}	-	P85	P24	A9	-
I/O	1	-	P23	D8	18
I/O	1	-	P22	C8	21

XC2S15 Device Pinouts (Continued)

XC2S15 Pad Name		VQ100	TQ144	CS144	Bndry Scan
Function	Bank				
I/O, V _{REF}	1	P86	P21	B8	24
I/O	1	-	P20	A8	27
I/O	1	P87	P19	B7	30
I, GCK2	1	P88	P18	A7	36
GND	-	P89	P17	C7	-
V _{CCO}	1	P90	P16	D7	-
V _{CCO}	0	P90	P16	D7	-
I, GCK3	0	P91	P15	A6	37
V _{CCINT}	-	P92	P14	B6	-
I/O	0	-	P13	C6	44
I/O, V _{REF}	0	P93	P12	D6	47
I/O	0	-	P11	A5	50
I/O	0	-	P10	B5	53
V _{CCINT}	-	P94	P9	C5	-
GND	-	-	P8	D5	-
I/O	0	P95	P7	A4	56
I/O	0	P96	P6	B4	59
I/O, V _{REF}	0	P97	P5	C4	62
I/O	0	-	P4	A3	65
I/O	0	P98	P3	B3	68
TCK	-	P99	P2	C3	-
V _{CCO}	0	P100	P1	A2	-
V _{CCO}	7	P100	P144	B2	-

04/18/01

Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. See "VCCO Banks" for details on V_{CCO} banking.

Additional XC2S15 Package Pins

VQ100

Not Connected Pins					
P28	P29	-	-	-	-

11/02/00

TQ144

Not Connected Pins					
P42	P64	P78	P101	P104	P105
P116	P138	-	-	-	-

11/02/00

CS144

Not Connected Pins					
D3	D12	J4	K13	M3	M4
M10	N3	-	-	-	-

11/02/00

XC2S50 Device Pinouts (Continued)

XC2S50 Pad Name		TQ144	PQ208	FG256	Bndry Scan
Function	Bank				
I/O	3	-	-	J14	503
I/O	3	P56	P127	K15	506
V _{CCINT}	-	P55	P128	V _{CCINT} *	-
I/O, TRDY ⁽¹⁾	3	P54	P129	J15	512
V _{CCO}	3	P53	P130	V _{CCO} Bank 3*	-
V _{CCO}	2	P53	P130	V _{CCO} Bank 2*	-
GND	-	P52	P131	GND*	-
I/O, IRDY ⁽¹⁾	2	P51	P132	H16	515
I/O	2	-	P133	H14	518
I/O	2	P50	P134	H15	521
I/O	2	-	-	J13	524
I/O (D3)	2	P49	P135	G16	527
I/O, V _{REF}	2	P48	P136	H13	530
GND	-	-	P137	GND*	-
I/O	2	-	P138	G14	533
I/O	2	-	P139	G15	536
I/O	2	-	P140	G12	539
I/O	2	-	-	F16	542
I/O	2	P47	P141	G13	545
I/O (D2)	2	P46	P142	F15	548
V _{CCINT}	-	-	P143	V _{CCINT} *	-
V _{CCO}	2	-	P144	V _{CCO} Bank 2*	-
GND	-	P45	P145	GND*	-
I/O (D1)	2	P44	P146	E16	551
I/O	2	P43	P147	F14	554
I/O	2	P42	P148	D16	557
I/O	2	-	-	F12	560
I/O	2	-	P149	E15	563
I/O, V _{REF}	2	P41	P150	F13	566
GND	-	-	-	GND*	-
I/O	2	-	P151	E14	569
I/O	2	-	-	C16	572
I/O	2	P40	P152	E13	575
I/O	2	-	-	B16	578
I/O (DIN, D0)	2	P39	P153	D14	581
I/O (DOUT, BUSY)	2	P38	P154	C15	584
CCLK	2	P37	P155	D15	587
V _{CCO}	2	P36	P156	V _{CCO} Bank 2*	-

XC2S50 Device Pinouts (Continued)

XC2S50 Pad Name		TQ144	PQ208	FG256	Bndry Scan
Function	Bank				
V _{CCO}	1	P35	P156	V _{CCO} Bank 1*	-
TDO	2	P34	P157	B14	-
GND	-	P33	P158	GND*	-
TDI	-	P32	P159	A15	-
I/O ($\overline{\text{CS}}$)	1	P31	P160	B13	0
I/O ($\overline{\text{WRITE}}$)	1	P30	P161	C13	3
I/O	1	-	-	C12	6
I/O	1	P29	P162	A14	9
I/O	1	-	-	D12	12
I/O	1	-	P163	B12	15
GND	-	-	-	GND*	-
I/O, V _{REF}	1	P28	P164	C11	18
I/O	1	-	P165	A13	21
I/O	1	-	-	D11	24
I/O	1	-	P166	A12	27
I/O	1	P27	P167	E11	30
I/O	1	P26	P168	B11	33
GND	-	P25	P169	GND*	-
V _{CCO}	1	-	P170	V _{CCO} Bank 1*	-
V _{CCINT}	-	P24	P171	V _{CCINT} *	-
I/O	1	P23	P172	A11	36
I/O	1	P22	P173	C10	39
I/O	1	-	P174	B10	45
I/O	1	-	P175	D10	48
I/O	1	-	P176	A10	51
GND	-	-	P177	GND*	-
I/O, V _{REF}	1	P21	P178	B9	54
I/O	1	-	P179	E10	57
I/O	1	-	-	A9	60
I/O	1	P20	P180	D9	63
I/O	1	P19	P181	A8	66
I, GCK2	1	P18	P182	C9	72
GND	-	P17	P183	GND*	-
V _{CCO}	1	P16	P184	V _{CCO} Bank 1*	-
V _{CCO}	0	P16	P184	V _{CCO} Bank 0*	-
I, GCK3	0	P15	P185	B8	73
V _{CCINT}	-	P14	P186	V _{CCINT} *	-
I/O	0	P13	P187	A7	80

XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name		TQ144	PQ208	FG256	FG456	Bndry Scan
Function	Bank					
I/O, V _{REF}	4	P79	P95	T11	AB16	502
I/O	4	-	-	-	AB17	505
I/O	4	P78	P96	N11	V15	508
I/O	4	-	-	R12	Y16	511
I/O	4	-	P97	P11	AB18	517
I/O, V _{REF}	4	P77	P98	T12	AB19	520
V _{CCO}	4	-	-	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
GND	-	-	-	GND*	GND*	-
I/O	4	-	P99	T13	Y17	523
I/O	4	-	-	N12	V16	526
I/O	4	-	-	-	W17	529
I/O	4	P76	P100	R13	AB20	532
I/O	4	-	-	P12	AA19	535
I/O	4	P75	P101	P13	AA20	541
I/O	4	P74	P102	T14	W18	544
GND	-	P73	P103	GND*	GND*	-
DONE	3	P72	P104	R14	Y19	547
V _{CCO}	4	P71	P105	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
V _{CCO}	3	P70	P105	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
PROGRAM	-	P69	P106	P15	W20	550
I/O (INIT)	3	P68	P107	N15	V19	551
I/O (D7)	3	P67	P108	N14	Y21	554
I/O	3	-	-	T15	W21	560
I/O	3	P66	P109	M13	U20	563
I/O	3	-	-	-	U19	566
I/O	3	-	-	R16	T18	569
I/O	3	-	P110	M14	W22	572
GND	-	-	-	GND*	GND*	-
V _{CCO}	3	-	-	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
I/O, V _{REF}	3	P65	P111	L14	U21	575
I/O	3	-	P112	M15	T20	578
I/O	3	-	-	L12	T21	584
I/O	3	P64	P113	P16	R18	587
I/O	3	-	-	-	U22	590
I/O, V _{REF}	3	P63	P114	L13	R19	593
I/O (D6)	3	P62	P115	N16	T22	596
GND	-	P61	P116	GND*	GND*	-

XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name		TQ144	PQ208	FG256	FG456	Bndry Scan
Function	Bank					
V _{CCO}	3	-	P117	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
V _{CCINT}	-	-	P118	V _{CCINT} *	V _{CCINT} *	-
I/O (D5)	3	P60	P119	M16	R21	599
I/O	3	P59	P120	K14	P18	602
I/O	3	-	-	L16	P20	605
I/O	3	-	P121	K13	P21	608
I/O	3	-	P122	L15	N18	614
I/O	3	-	P123	K12	N20	617
GND	-	-	P124	GND*	GND*	-
I/O, V _{REF}	3	P58	P125	K16	N21	620
I/O (D4)	3	P57	P126	J16	N22	623
I/O	3	-	-	J14	M19	626
I/O	3	P56	P127	K15	M20	629
V _{CCINT}	-	P55	P128	E5	V _{CCINT} *	-
I/O, TRDY ⁽¹⁾	3	P54	P129	J15	M22	638
V _{CCO}	3	P53	P130	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
V _{CCO}	2	P53	P130	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P52	P131	GND*	GND*	-
I/O, IRDY ⁽¹⁾	2	P51	P132	H16	L20	641
I/O	2	-	P133	H14	L17	644
I/O	2	P50	P134	H15	L21	650
I/O	2	-	-	J13	L22	653
I/O (D3)	2	P49	P135	G16	K20	656
I/O, V _{REF}	2	P48	P136	H13	K21	659
GND	-	-	P137	GND*	GND*	-
I/O	2	-	P138	G14	K22	662
I/O	2	-	P139	G15	J21	665
I/O	2	-	P140	G12	J18	671
I/O	2	-	-	F16	J22	674
I/O	2	P47	P141	G13	H19	677
I/O (D2)	2	P46	P142	F15	H20	680
V _{CCINT}	-	-	P143	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	2	-	P144	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P45	P145	GND*	GND*	-
I/O (D1)	2	P44	P146	E16	H22	683
I/O, V _{REF}	2	P43	P147	F14	H18	686
I/O	2	-	-	-	G21	689
I/O	2	P42	P148	D16	G18	692

XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name		TQ144	PQ208	FG256	FG456	Bndry Scan
Function	Bank					
I/O	2	-	-	F12	G20	695
I/O	2	-	P149	E15	F19	701
I/O, V _{REF}	2	P41	P150	F13	F21	704
V _{CCO}	2	-	-	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	-	-	GND*	GND*	-
I/O	2	-	P151	E14	F20	707
I/O	2	-	-	C16	F18	710
I/O	2	-	-	-	E21	713
I/O	2	P40	P152	E13	D22	716
I/O	2	-	-	B16	E20	719
I/O (DIN, DO)	2	P39	P153	D14	D20	725
I/O (DOUT, BUSY)	2	P38	P154	C15	C21	728
CCLK	2	P37	P155	D15	B22	731
V _{CCO}	2	P36	P156	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
V _{CCO}	1	P35	P156	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
TDO	2	P34	P157	B14	A21	-
GND	-	P33	P158	GND*	GND*	-
TDI	-	P32	P159	A15	B20	-
I/O ($\overline{\text{CS}}$)	1	P31	P160	B13	C19	0
I/O ($\overline{\text{WRITE}}$)	1	P30	P161	C13	A20	3
I/O	1	-	-	C12	D17	9
I/O	1	P29	P162	A14	A19	12
I/O	1	-	-	-	B18	15
I/O	1	-	-	D12	C17	18
I/O	1	-	P163	B12	D16	21
GND	-	-	-	GND*	GND*	-
V _{CCO}	1	-	-	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
I/O, V _{REF}	1	P28	P164	C11	A18	24
I/O	1	-	P165	A13	B17	27
I/O	1	-	-	D11	D15	33
I/O	1	-	P166	A12	C16	36
I/O	1	-	-	-	D14	39
I/O, V _{REF}	1	P27	P167	E11	E14	42
I/O	1	P26	P168	B11	A16	45
GND	-	P25	P169	GND*	GND*	-

XC2S100 Device Pinouts (Continued)

XC2S100 Pad Name		TQ144	PQ208	FG256	FG456	Bndry Scan
Function	Bank					
V _{CCO}	1	-	P170	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
V _{CCINT}	-	P24	P171	V _{CCINT} *	V _{CCINT} *	-
I/O	1	P23	P172	A11	C15	48
I/O	1	P22	P173	C10	B15	51
I/O	1	-	-	-	F12	54
I/O	1	-	P174	B10	C14	57
I/O	1	-	P175	D10	D13	63
I/O	1	-	P176	A10	C13	66
GND	-	-	P177	GND*	GND*	-
I/O, V _{REF}	1	P21	P178	B9	B13	69
I/O	1	-	P179	E10	E12	72
I/O	1	-	-	A9	B12	75
I/O	1	P20	P180	D9	D12	78
I/O	1	P19	P181	A8	D11	84
I, GCK2	1	P18	P182	C9	A11	90
GND	-	P17	P183	GND*	GND*	-
V _{CCO}	1	P16	P184	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
V _{CCO}	0	P16	P184	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
I, GCK3	0	P15	P185	B8	C11	91
V _{CCINT}	-	P14	P186	V _{CCINT} *	V _{CCINT} *	-
I/O	0	P13	P187	A7	A10	101
I/O	0	-	-	D8	B10	104

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O, IRDY ⁽¹⁾	2	P132	H16	L20	767
I/O	2	P133	H14	L17	770
I/O	2	-	-	L18	773
I/O	2	P134	H15	L21	776
I/O	2	-	J13	L22	779
I/O (D3)	2	P135	G16	K20	782
I/O, V _{REF}	2	P136	H13	K21	785
V _{CCO}	2	-	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P137	GND*	GND*	-
I/O	2	P138	G14	K22	788
I/O	2	P139	G15	J21	791
I/O	2	-	-	J20	797
I/O	2	P140	G12	J18	800
I/O	2	-	F16	J22	803
I/O	2	-	-	J19	806
I/O	2	P141	G13	H19	812
I/O (D2)	2	P142	F15	H20	815
V _{CCINT}	-	P143	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	2	P144	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P145	GND*	GND*	-
I/O (D1)	2	P146	E16	H22	818
I/O, V _{REF}	2	P147	F14	H18	821
I/O	2	-	-	G21	824
I/O	2	P148	D16	G18	827
I/O	2	-	F12	G20	830
I/O	2	-	-	G19	833
I/O	2	-	-	F22	836
I/O	2	P149	E15	F19	839
I/O, V _{REF}	2	P150	F13	F21	842
V _{CCO}	2	-	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	-	GND*	GND*	-
I/O	2	P151	E14	F20	845
I/O	2	-	C16	F18	848
I/O	2	-	-	E22	851
I/O	2	-	-	E21	854
I/O	2	P152	E13	D22	857
GND	-	-	GND*	GND*	-
I/O	2	-	B16	E20	860
I/O	2	-	-	D21	863

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	2	-	-	C22	866
I/O (DIN, D0)	2	P153	D14	D20	869
I/O (DOUT, BUSY)	2	P154	C15	C21	872
CCLK	2	P155	D15	B22	875
V _{CCO}	2	P156	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
V _{CCO}	1	P156	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
TDO	2	P157	B14	A21	-
GND	-	P158	GND*	GND*	-
TDI	-	P159	A15	B20	-
I/O ($\overline{\text{CS}}$)	1	P160	B13	C19	0
I/O ($\overline{\text{WRITE}}$)	1	P161	C13	A20	3
I/O	1	-	-	B19	6
I/O	1	-	-	C18	9
I/O	1	-	C12	D17	12
GND	-	-	GND*	GND*	-
I/O	1	P162	A14	A19	15
I/O	1	-	-	B18	18
I/O	1	-	-	E16	21
I/O	1	-	D12	C17	24
I/O	1	P163	B12	D16	27
GND	-	-	GND*	GND*	-
V _{CCO}	1	-	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
I/O, V _{REF}	1	P164	C11	A18	30
I/O	1	P165	A13	B17	33
I/O	1	-	-	E15	36
I/O	1	-	-	A17	39
I/O	1	-	D11	D15	42
I/O	1	P166	A12	C16	45
I/O	1	-	-	D14	48
I/O, V _{REF}	1	P167	E11	E14	51
I/O	1	P168	B11	A16	54
GND	-	P169	GND*	GND*	-
V _{CCO}	1	P170	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
V _{CCINT}	-	P171	V _{CCINT} *	V _{CCINT} *	-
I/O	1	P172	A11	C15	57
I/O	1	P173	C10	B15	60
I/O	1	-	-	A15	66
I/O	1	-	-	F12	69

Additional XC2S150 Package Pins

PQ208

Not Connected Pins					
P55	P56	-	-	-	-

11/02/00

FG256

V _{CCINT} Pins					
C3	C14	D4	D13	E5	E12
M5	M12	N4	N13	P3	P14
V _{CCO} Bank 0 Pins					
E8	F8	-	-	-	-
V _{CCO} Bank 1 Pins					
E9	F9	-	-	-	-
V _{CCO} Bank 2 Pins					
H11	H12	-	-	-	-
V _{CCO} Bank 3 Pins					
J11	J12	-	-	-	-
V _{CCO} Bank 4 Pins					
L9	M9	-	-	-	-
V _{CCO} Bank 5 Pins					
L8	M8	-	-	-	-
V _{CCO} Bank 6 Pins					
J5	J6	-	-	-	-
V _{CCO} Bank 7 Pins					
H5	H6	-	-	-	-
GND Pins					
A1	A16	B2	B15	F6	F7
F10	F11	G6	G7	G8	G9
G10	G11	H7	H8	H9	H10
J7	J8	J9	J10	K6	K7
K8	K9	K10	K11	L6	L7
L10	L11	R2	R15	T1	T16
Not Connected Pins					
P4	R4	-	-	-	-

11/02/00

Additional XC2S150 Package Pins (Continued)

FG456

V _{CCINT} Pins					
E5	E18	F6	F17	G7	G8
G9	G14	G15	G16	H7	H16
J7	J16	P7	P16	R7	R16
T7	T8	T9	T14	T15	T16
U6	U17	V5	V18	-	-
V _{CCO} Bank 0 Pins					
F7	F8	F9	F10	G10	G11
V _{CCO} Bank 1 Pins					
F13	F14	F15	F16	G12	G13
V _{CCO} Bank 2 Pins					
G17	H17	J17	K16	K17	L16
V _{CCO} Bank 3 Pins					
M16	N16	N17	P17	R17	T17
V _{CCO} Bank 4 Pins					
T12	T13	U13	U14	U15	U16
V _{CCO} Bank 5 Pins					
T10	T11	U7	U8	U9	U10
V _{CCO} Bank 6 Pins					
M7	N6	N7	P6	R6	T6
V _{CCO} Bank 7 Pins					
G6	H6	J6	K6	K7	L7
GND Pins					
A1	A22	B2	B21	C3	C20
J9	J10	J11	J12	J13	J14
K9	K10	K11	K12	K13	K14
L9	L10	L11	L12	L13	L14
M9	M10	M11	M12	M13	M14
N9	N10	N11	N12	N13	N14
P9	P10	P11	P12	P13	P14
Y3	Y20	AA2	AA21	AB1	AB22
Not Connected Pins					
A2	A6	A12	A13	A14	B11
B16	C2	C8	C9	D1	D4
D18	D19	E13	E17	E19	F11
G2	G22	H21	J1	J4	K2
K18	K19	L2	L19	M2	M17
M21	N1	P1	P5	P22	R3
R20	R22	U3	U18	V6	W4
W13	W15	W19	Y5	Y22	AA1
AA3	AA9	AA10	AA11	AA16	AB7
AB8	AB12	AB14	AB21	-	-

11/02/00

XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
V _{CCO}	1	P156	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
TDO	2	P157	B14	A21	-
GND	-	P158	GND*	GND*	-
TDI	-	P159	A15	B20	-
I/O ($\overline{\text{CS}}$)	1	P160	B13	C19	0
I/O ($\overline{\text{WRITE}}$)	1	P161	C13	A20	3
I/O	1	-	-	B19	9
I/O	1	-	-	C18	12
I/O	1	-	C12	D17	15
GND	-	-	GND*	GND*	-
I/O, V _{REF}	1	P162	A14	A19	18
I/O	1	-	-	B18	21
I/O	1	-	-	E16	27
I/O	1	-	D12	C17	30
I/O	1	P163	B12	D16	33
GND	-	-	GND*	GND*	-
V _{CCO}	1	-	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
I/O, V _{REF}	1	P164	C11	A18	36
I/O	1	P165	A13	B17	39
I/O	1	-	-	E15	42
I/O	1	-	-	A17	45
I/O	1	-	D11	D15	48
GND	-	-	GND*	GND*	-
I/O	1	P166	A12	C16	51
I/O	1	-	-	D14	54
I/O, V _{REF}	1	P167	E11	E14	60
I/O	1	P168	B11	A16	63
GND	-	P169	GND*	GND*	-
V _{CCO}	1	P170	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
V _{CCINT}	-	P171	V _{CCINT} *	V _{CCINT} *	-
I/O	1	P172	A11	C15	66
I/O	1	P173	C10	B15	69
I/O	1	-	-	E13	72
I/O	1	-	-	A15	75
I/O	1	-	-	F12	78
GND	-	-	GND*	GND*	-
I/O	1	P174	B10	C14	81
I/O	1	-	-	B14	84
I/O	1	-	-	A14	87

XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	1	P175	D10	D13	90
I/O	1	P176	A10	C13	93
GND	-	P177	GND*	GND*	-
V _{CCO}	1	-	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
I/O, V _{REF}	1	P178	B9	B13	96
I/O	1	P179	E10	E12	99
I/O	1	-	-	A13	105
I/O	1	-	A9	B12	108
I/O	1	P180	D9	D12	111
I/O	1	-	-	C12	114
I/O	1	P181	A8	D11	120
I, GCK2	1	P182	C9	A11	126
GND	-	P183	GND*	GND*	-
V _{CCO}	1	P184	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
V _{CCO}	0	P184	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
I, GCK3	0	P185	B8	C11	127
V _{CCINT}	-	P186	V _{CCINT} *	V _{CCINT} *	-
I/O	0	-	-	E11	137
I/O	0	P187	A7	A10	140
I/O	0	-	D8	B10	143
I/O	0	-	-	F11	146
I/O	0	P188	A6	C10	152
I/O, V _{REF}	0	P189	B7	A9	155
V _{CCO}	0	-	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
GND	-	P190	GND*	GND*	-
I/O	0	P191	C8	B9	158
I/O	0	P192	D7	E10	161
I/O	0	-	-	C9	164
I/O	0	-	-	D10	167
I/O	0	P193	E7	A8	170
GND	-	-	GND*	GND*	-
I/O	0	-	-	D9	173
I/O	0	-	-	B8	176
I/O	0	-	-	C8	179
I/O	0	P194	C7	E9	182
I/O	0	P195	B6	A7	185
V _{CCINT}	-	P196	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	0	P197	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-